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02/15/02

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PATENT NUMBER and
ISSUE DATE
6515910

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10076826	02/15/2002	365	15.22	2818	HOANG, HUAN

**APPLICANTS: Lee Peter; Tsao Hsing-Ya; Tran Tam; Hsu Fu-Chang;

**CONTINUING DATA VERIFIED: *W*
THIS APPLN CLAIMS BENEFIT OF 60/273,585 03/06/2001

** FOREIGN APPLICATIONS VERIFIED: *W*

PG-PUB DO NOT PUBLISH ☒

RESCIND ☐

Foreign priority claimed ☐ yes ☒ no
35 USC 119 conditions met ☐ yes ☒ no
Verified and Acknowledged Examiners's initials *W*

ATTORNEY DOCKET NO

AP01-005

TITLE : Bit-by-bit Vt-correction operation for nonvolatile semiconductor one-transistor cell, nor-type flash EEPROM

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED

10-23-02

ISSUE FEE
Amount Due *640*
Date Paid *12-9-02*

☐ TERMINAL

DISCLAIMER

Assistant Examiner

Huan
HUANG HOANG
PRIMARY EXAMINER
Primary Examiner

PREPARED FOR ISSUE

CLAIMS ALLOWED

Total Claims *25*
Print Claim for O.G. *1*

DRAWING

Sheets Drwg. *15* Figs. Drwg. *17* Print Fig. *7A*

Haves 10/30/02
Application Examiner

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Drawing

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